

Enhancement Mode N-Channel Power MOSFET

PDFN5X6/NMOS/100V/ \pm 20V/3.0V/60A/8.0m Ω

Rev_{0.1}





100V, 8.0mΩ, 60A, N-Channel MOSFET

1.Features

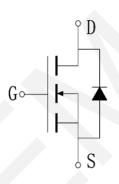
- ◆ 100V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V
- ♦ 100% RG Tested
- ◆ 100% UIS Tested

2.Applications

- Power Switching Application
- ◆ Load Switching



V _{DS}	R _{DS(on)} Typ.	I _D Max.
100V	8.0mΩ @ 10V	60A



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Part no. Marking		PCS/Reel	PCS/CTN.	
WX080N10PA	080N10	PDFN5X6	5,000	50,000	

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{ extsf{DSS}}$	100	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	I _D	60	А
Drain Current (Pulse), PW≤300μs	I _{DP}	240	А
Total Dissipation	P_{D}	114	W
Avalanche Energy, Single Pulsed	E _{AS}	165	mJ
Junction Temperature	T _j	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5.Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	R _{eJC}	1.1	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

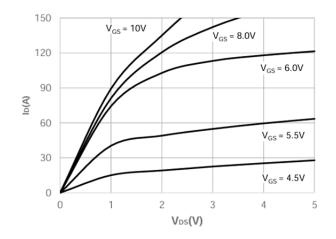
6.Electrical Characteristics at Ta=25°C (Note 3)

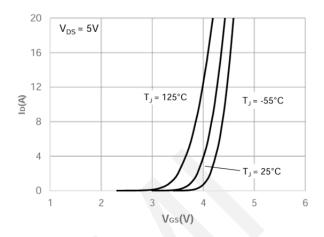
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 100V, V_{GS} = 0V$	-	1	1	μΑ
Gate to Source Leakage Current	I _{GSS1}	$V_{GS} = \pm 20V, V_{SS} = 0V$	ı	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =250μA	2.5	3.0	3.5	٧
Static Drain to Source On-State Resistance	R _{DS(on)}	I _D = 20A, V _{GS} = 10V	1	8.0	10	mΩ
Input Capacitance	C_{iss}	V _{GS} =0V,	-	1532	1	pF
Output Capacitance	C _{oss}	V _{DS} =50V,	-	643	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	-	21	-	pF
Turn-ON Delay Time	t _{d(on)}		-	11	-	ns
Rise Time	t _r	V _{DD} = 50V,	-	21	-	ns
Turn-OFF Delay Time	t _{d(off)}	$V_{GS} = 10V$, $R_{GEN} = 3\Omega$, $I_D = 20A$	ı	23	1	ns
Fall Time	t _f		1	8.8	1	ns
	Q_g	$V_{DS} = 50V,$ $V_{GS} = 0 \text{ to } 10V,$ $I_{D} = 20A$	ı	27	ı	nC
Total Gate Charge	Q_{gs}		-	7.6	-	nC
	Q_{gd}		-	8.1	-	nC
Diode Forward Voltage	V_{FSD}	I _S = 20A, V _{GS} = 0	0.5	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

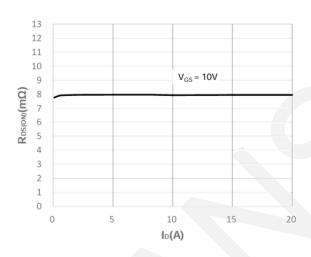


7. Typical electrical and thermal characteristics

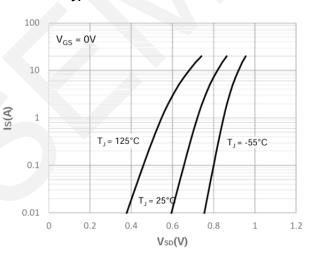




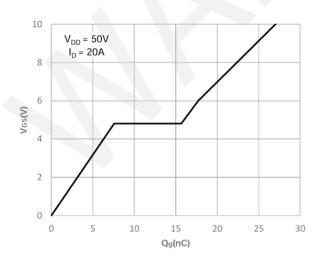
Output Characteristics



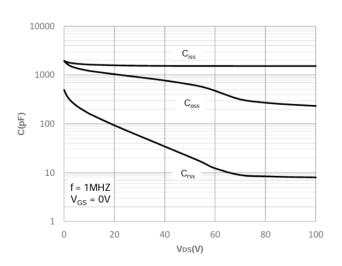
Typical Transfer Characteristics



On-resistance vs. Drain Current



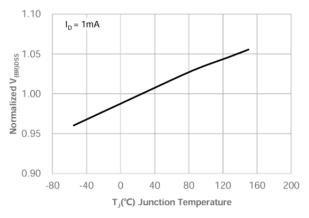
Body Diode Characteristics

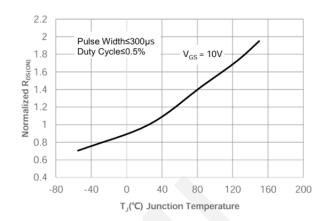


Gate Charge Characteristics

Capacitance Characteristics

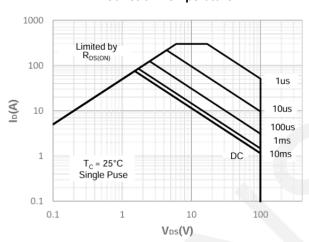




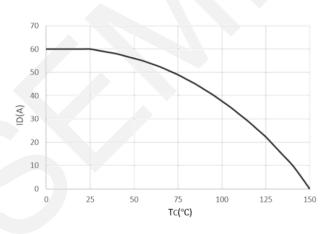


Normalized on Resistance vs.

Junction Temperature



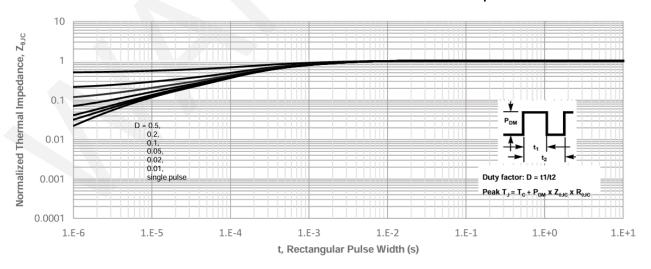
VBR(DSS) vs. Junction Temperature



Maximum Safe Operating Area

Maximum Continuous Drain Current vs.

Case Temperature

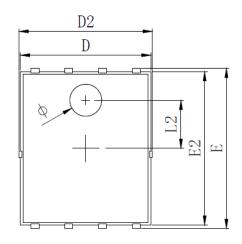


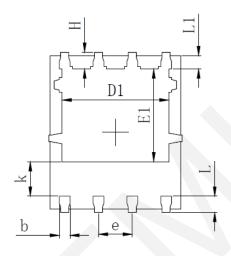
Normalized Maximum Transient

Thermal Impedance



8.Package Dimensions





SYMBOL	MILLIMETER			
	MIN	Тур.	MAX	
A	0. 900	1. 000	1. 100	
A1		0. 254 REF.		
A2	0~0. 05			
D	4. 824	4. 900	4. 976	
D1	3. 910	4. 010	4. 110	
D2	4. 924	5. 000	5. 076	
E	5. 924	6. 000	6. 076	
E1	3. 375	3. 475	3. 575	
E2	5. 674	5. 750	5. 826	
b	0. 350	0. 400	0. 450	
е	1.270 TYP.			
L	0. 534	0. 610	0. 686	
L1	0. 424	0. 500	0. 576	
L2	1.800 REF.			
k	1. 190	1. 290	1. 390	
Н	0. 549	0. 625	0. 701	
θ	8°	10°	12°	
ф	1. 100	1. 200	1. 300	
d			0. 100	



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